

Most Frequently Occurring Classifications of Patents Returned
From A Search of 10790301 on July 19, 2005

Original Classifications

3 600/407
2 73/579
2 348/163
2 356/497
2 359/9
2 600/442
2 702/14

Cross-Reference Classifications

3 324/76.19
3 356/432
3 600/476
2 73/599
2 73/602
2 73/61.49
2 73/61.79
2 324/307
2 324/457
2 356/511
2 359/29
2 359/32
2 378/17
2 378/901
2 455/306
2 600/442
2 702/76

Combined Classifications

4 600/407
4 600/442
3 73/599
3 324/76.19
3 356/432
3 600/476
2 73/579
2 73/602
2 73/61.49
2 73/61.79
2 250/363.04
2 324/307
2 324/457
2 348/163
2 356/497
2 356/511
2 359/29
2 359/32
2 359/9
2 378/17
2 378/4
2 378/901
2 455/306
2 600/425
2 702/14
2 702/76

PLUS
Report

Titles of Most Frequently Occurring Classifications of Patents Returned
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- 4 600/407 (3 OR, 1 XR)
 Class 600 : SURGERY
 600/300 DIAGNOSTIC TESTING
 600/407 .Detecting nuclear, electromagnetic, or
 ultrasonic radiation

- 4 600/442 (2 OR, 2 XR)
 Class 600 : SURGERY
 600/300 DIAGNOSTIC TESTING
 600/407 .Detecting nuclear, electromagnetic, or
 ultrasonic radiation
 600/437 ..Ultrasonic
 600/442 ...Tissue attenuation or impedance measurement
 or compensation

- 3 73/599 (1 OR, 2 XR)
 Class 073 : MEASURING AND TESTING
 73/570 VIBRATION
 73/584 .By mechanical waves
 73/596 ..Beamed
 73/599 ...Attenuation measurement

- 3 324/76.19 (0 OR, 3 XR)
 Class 324 : ELECTRICITY: MEASURING AND TESTING
 324/76.11 MEASURING, TESTING, OR SENSING ELECTRICITY, PER
 SE
 324/76.12 .Analysis of complex waves
 324/76.19 ..Frequency spectrum analyzer

- 3 356/432 (0 OR, 3 XR)
 Class 356 : OPTICS: MEASURING AND TESTING
 356/432 FOR LIGHT TRANSMISSION OR ABSORPTION

- 3 600/476 (0 OR, 3 XR)
 Class 600 : SURGERY
 600/300 DIAGNOSTIC TESTING
 600/407 .Detecting nuclear, electromagnetic, or
 ultrasonic radiation
 600/476 ..Visible light radiation

- 2 73/579 (2 OR, 0 XR)
 Class 073 : MEASURING AND TESTING
 73/570 VIBRATION
 73/579 .Resonance, frequency, or amplitude study

- 2 73/602 (0 OR, 2 XR)
 Class 073 : MEASURING AND TESTING
 73/570 VIBRATION
 73/584 .By mechanical waves
 73/596 ..Beamed
 73/602 ...with signal analyzing or mathematical
 processing

- 2 73/61.49 (0 OR, 2 XR)
 Class 073 : MEASURING AND TESTING
 73/53.01 LIQUID ANALYSIS OR ANALYSIS OF THE SUSPENSION
 OF SOLIDS IN A LIQUID
 73/61.41 .Content or effect of a constituent of a liquid
 mixture

- 73/61.43 ..Liquid constituent of a liquid mixture
73/61.49 ...By vibration
- 2 73/61.79 (0 OR, 2 XR)
Class 073 : MEASURING AND TESTING
73/53.01 LIQUID ANALYSIS OR ANALYSIS OF THE SUSPENSION
OF SOLIDS IN A LIQUID
73/61.41 .Content or effect of a constituent of a liquid
mixture
73/61.79 ..By vibration
- 2 250/363.04 (1 OR, 1 XR)
Class 250 : RADIANT ENERGY
250/336.1 INVISIBLE RADIANT ENERGY RESPONSIVE ELECTRIC
SIGNALLING
250/361R .With or including a luminophor
250/363.01 ..With radiant energy source
250/363.02 ...Body scanner or camera
250/363.04Emission tomography
- 2 324/307 (0 OR, 2 XR)
Class 324 : ELECTRICITY: MEASURING AND TESTING
324/300 PARTICLE PRECESSION RESONANCE
324/307 .Using a nuclear resonance spectrometer system
- 2 324/457 (0 OR, 2 XR)
Class 324 : ELECTRICITY: MEASURING AND TESTING
324/457 ELECTROSTATIC FIELD
- 2 348/163 (2 OR, 0 XR)
Class 348 : TELEVISION
348/162 RESPONSIVE TO NONVISIBLE ENERGY
348/163 .Sonic or ultrasonic
- 2 356/497 (2 OR, 0 XR)
Class 356 : OPTICS: MEASURING AND TESTING
356/450 BY LIGHT INTERFERENCE (E.G., INTERFEROMETER)
356/496 .For dimensional measurement
356/497 ..Having short coherence length source
- 2 356/511 (0 OR, 2 XR)
Class 356 : OPTICS: MEASURING AND TESTING
356/450 BY LIGHT INTERFERENCE (E.G., INTERFEROMETER)
356/496 .For dimensional measurement
356/511 ..Contour or profile
- 2 359/29 (0 OR, 2 XR)
Class 359 : OPTICS: SYSTEMS
359/1 HOLOGRAPHIC SYSTEM OR ELEMENT
359/29 .Fourier transform holography
- 2 359/32 (0 OR, 2 XR)
Class 359 : OPTICS: SYSTEMS
359/1 HOLOGRAPHIC SYSTEM OR ELEMENT
359/32 .For reconstructing image
- 2 359/9 (2 OR, 0 XR)
Class 359 : OPTICS: SYSTEMS
359/1 HOLOGRAPHIC SYSTEM OR ELEMENT
359/9 .For synthetically generating a hologram
- 2 378/17 (0 OR, 2 XR)

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Class	378 :	X-RAY OR GAMMA RAY SYSTEMS OR DEVICES
378/1		SPECIFIC APPLICATION
378/4		.Computerized tomography
378/17		..Tiltable or nonvertical examination plane

2 378/4 (1 OR, 1 XR)

Class	378 :	X-RAY OR GAMMA RAY SYSTEMS OR DEVICES
378/1		SPECIFIC APPLICATION
378/4		.Computerized tomography

2 378/901 (0 OR, 2 XR)

Class	378 :	X-RAY OR GAMMA RAY SYSTEMS OR DEVICES
378/901		COMPUTER TOMOGRAPHY PROGRAM OR PROCESSOR

2 455/306 (0 OR, 2 XR)

Class	455 :	TELECOMMUNICATIONS
455/130		RECEIVER OR ANALOG MODULATED SIGNAL FREQUENCY CONVERTER
455/296		.Noise or interference elimination
455/303		..Using plural separate signal paths
455/305		...With balancing or neutralizing
455/306	Filter in at least one path

2 600/425 (1 OR, 1 XR)

Class	600 :	SURGERY
600/300		DIAGNOSTIC TESTING
600/407		.Detecting nuclear, electromagnetic, or ultrasonic radiation
600/425		..With tomographic imaging obtained from electromagnetic wave

2 702/14 (2 OR, 0 XR)

Class	702 :	DATA PROCESSING: MEASURING, CALIBRATING, OR TESTING
702/1		MEASUREMENT SYSTEM IN A SPECIFIC ENVIRONMENT
702/2		.Earth science
702/14		..Seismology

2 702/76 (0 OR, 2 XR)

Class	702 :	DATA PROCESSING: MEASURING, CALIBRATING, OR TESTING
702/1		MEASUREMENT SYSTEM IN A SPECIFIC ENVIRONMENT
702/57		.Electrical signal parameter measurement system
702/66		..Waveform analysis
702/75		...Frequency
702/76	Frequency spectrum

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6298110 48
5995904 43
6075836 43
5406478 41
5343149 39
6549801 38
6374189 38
4797923 37
5499095 37
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5963929 33
5828216 32
4623855 32
4950042 32
5930384 32

PLUS Search Results for S/N 10790301, Searched July 19, 2005

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